

# FQPF8N60CF 600V N-Channel MOSFET

#### **Features**

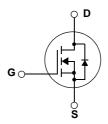
- 6.26A, 600V,  $R_{DS(on)}$  = 1.5 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 28 nC)
- Low Crss (typical 12 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability

### **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





# **Absolute Maximum Ratings**

Symbol	Parameter		FQPF8N60CFT	Units
V <sub>DSS</sub>	Drain-Source Voltage		600	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		6.26*	Α
	- Continuous (T <sub>C</sub> = 100°C)		3.96*	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	25*	А
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		160	mJ
I <sub>AR</sub>	Avalanche Current (Note 1		6.26	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		14.7	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		48	W
	- Derate above 25°C		0.38	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

<sup>\*</sup> Drain current limited by maximum junction temperature

#### **Thermal Characteristics**

Symbol	Parameter	FQPF8N60CF	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2.6	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W	

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FQPF8N60CFT	FQPF8N60CFT	TO-220F		-	50

# Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units		
Off Charac	Off Characteristics							
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600			V		
$\Delta BV_{DSS}/$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C		0.7		V/°C		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V			10	μΑ		
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C			100	μΑ		
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA		
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA		
On Charact	On Characteristics							
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V		
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3.13 A		1.25	1.5	Ω		
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> =3.13 A (Note 4)		8.7		S		
Dynamic Ch	Dynamic Characteristics							
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		965	1255	pF		
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		105	135	pF		
C <sub>rss</sub>	Reverse Transfer Capacitance			12	16	pF		
Switching C	Characteristics							
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_D = 6.26\text{A},$		16.5	45	ns		
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		60.5	130	ns		
t <sub>d(off)</sub>	Turn-Off Delay Time	41.4.5		81	170	ns		
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		64.5	140	ns		
Qg	Total Gate Charge	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 6.26A,		28	36	nC		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		4.5		nC		
$Q_{gd}$	Gate-Drain Charge	(Note 4, 5)		12		nC		
Drain-Source	ce Diode Characteristics and Maximum Ratings	3		1		11.		
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				6.26	Α		
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				25	Α		
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6.26 A			1.4	V		
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6.26 A,		82		ns		
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		242		nC		

#### NOTES

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 7.3mH, I<sub>AS</sub> = 6.26A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C
- 3.  $I_{SD} \le 6.26$ A, di/dt  $\le 200$ A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25$ °C
- 4. Pulse Test : Pulse width  $\leq 300 \mu s,$  Duty cycle  $\leq 2\%$
- 5. Essentially independent of operating temperature

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

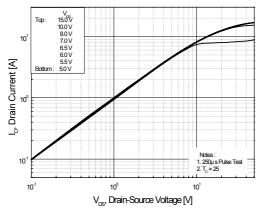


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

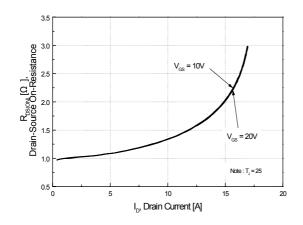


Figure 5. Capacitance Characteristics

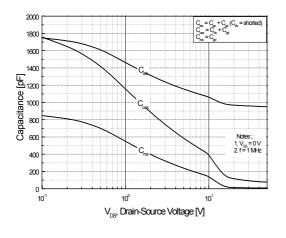


Figure 2. Transfer Characteristics

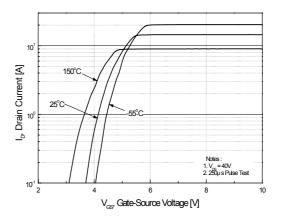


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

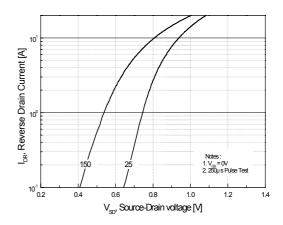
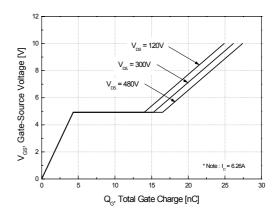


Figure 6. Gate Charge Characteristics



# Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

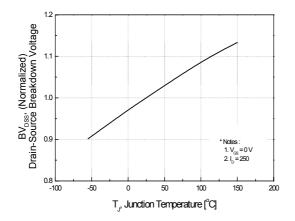


Figure 8. On-Resistance Variation vs. Temperature

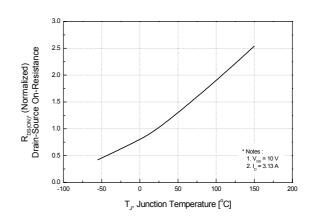
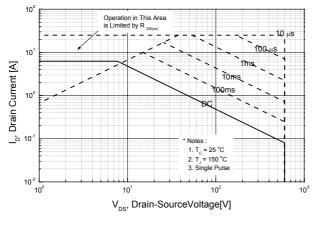


Figure 9. Maximum Safe Operating Area





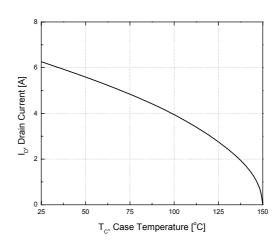
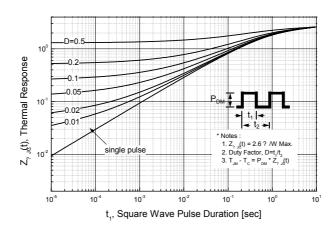
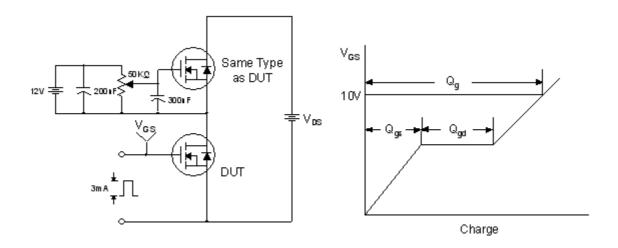


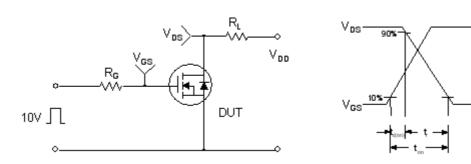
Figure 11. Transient Thermal Response Curve



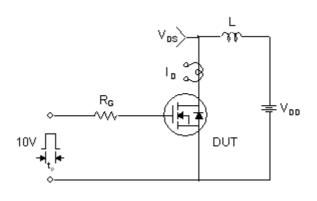
### **Gate Charge Test Circuit & Waveform**

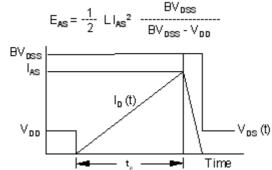


#### **Resistive Switching Test Circuit & Waveforms**

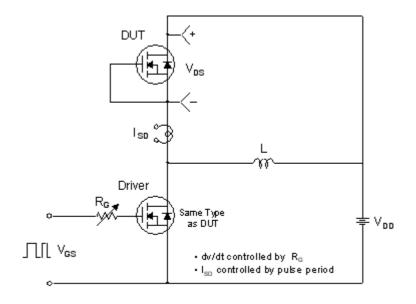


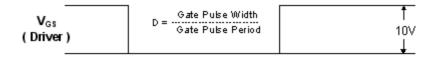
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

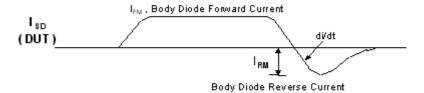


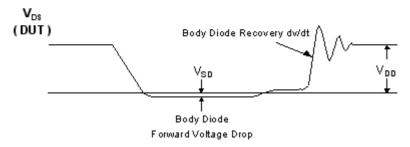


### Peak Diode Recovery dv/dt Test Circuit & Waveforms



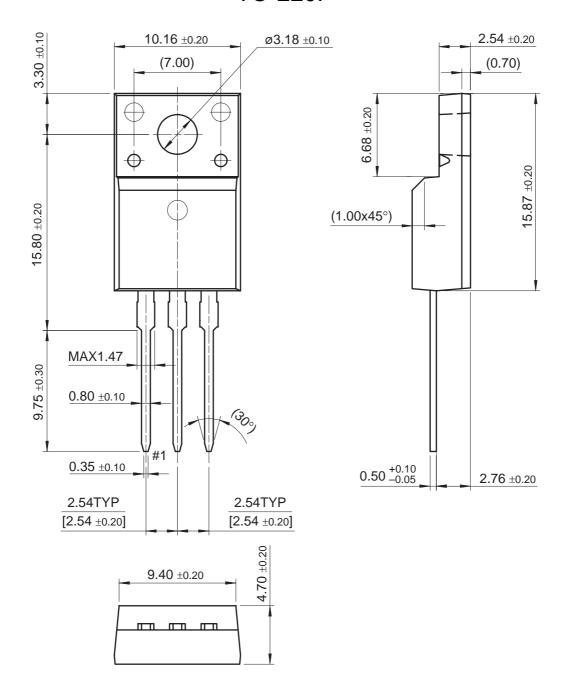






### **Mechanical Dimensions**

# TO-220F



Dimensions in Millimeters

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